N-Channel UniFET II MOSFET

600 V, 4 A, 2 Ω

UniFET II MOSFET is ON Semiconductor's high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on-state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2 kV HBM surge stress. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.

Features

- $R_{DS(on)} = 1.65 \Omega$ (Typ.) @ $V_{GS} = 10 V$, $I_D = 2 A$
- Low Gate Charge (Typ. 10 nC)
- Low C_{rss} (Typ. 5 pF)
- 100% Avalanche Tested
- Improved dv/dt Capability
- ESD Improved Capability
- These Devices are Pb-Free and are RoHS Compliant

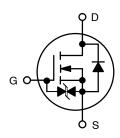
Applications

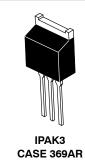
- LCD / LED TV
- Lighting
- Charger / Adapter



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ORDERING INFORMATION

See detailed ordering, marking and shipping information on page 2 of this data sheet.

MAXIMUM RATINGS ($T_C = 25^{\circ}C$ unless otherwise noted)

Symbol	Parameter	Value	Unit	
V _{DSS}	Drain-to-Source Voltage	600	V	
V _{GSS}	Gate-to-Source Voltage	±25	V	
I _D	Drain Current	Continuous (T _C = 25°C)	4	А
		Continuous (T _C = 100°C)	2.4	
I _{DM}	Drain Current	Pulsed (Note 1)	16	А
E _{AS}	Single Pulse Avalanche Energy (Note 2)	216	mJ	
I _{AR}	Avalanche Current (Note 1)	4	А	
E _{AR}	Repetitive Avalanche Energy (Note 1)		8.3	mJ
dv/dt	Peak Diode Recovery (Note 3)		10	V/ns
PD	Power Dissipation	$T_{C} = 25^{\circ}C$	83	W
		Derate Above 25°C	0.7	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range	-55 to +150	°C	
ΤL	Maximum Lead Temperature for Soldering Purposes (1/8	300	°C	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected. 1. Repetitive Rating: Pulse width limited by maximum junction temperature. 2. $I_{AS} = 4 \text{ A}, V_{DD} = 50 \text{ V}, L = 27 \text{ mH}, R_G = 25 \Omega$, starting $T_J = 25^{\circ}\text{C}$. 3. $I_{SD} \le 4 \text{ A}, \text{ di/dt} \le 200 \text{ A/}\mu\text{s}, V_{DD} \le \text{BV}_{DSS}$, Starting $T_J = 25^{\circ}\text{C}$.

THERMAL CHARACTERISTICS

Symbol	Parameter	Value	Unit
R_{\thetaJC}	Thermal Resistance, Junction-to-Case, Max.	1.5	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient, Max.	90	

PACKAGE MARKING AND ORDERING INFORMATION

Part Number	Top Mark	Package	Packing Method	Reel Size	Tape Width	Quantity
FDU5N60NZTU	FDU5N60NZ	IPAK	Tube	N/A	N/A	75 units

ELECTRICAL CHARACTERISTICS (T_C = 25°C unless otherwise specified)

Symbol	Parameter	Test Condition	Min	Тур	Max	Unit
OFF CHARA	CTERISTICS			-	-	-
BV _{DSS}	Drain-to-Source Breakdown Voltage	$I_D = 250 \ \mu\text{A}, \ V_{GS} = 0 \ V, \ T_J = 25^\circ\text{C}$	600	-	-	V
$\Delta \text{BV}_{\text{DSS}} / \Delta \text{T}_{\text{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 µA, Referenced to 25°C	-	0.6	-	V/∘C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = 600 \text{ V}, V_{GS} = 0 \text{ V}$	-	-	50	μΑ
		V_{DS} = 480 V, T_{C} = 125°C	-	-	100	
I _{GSS}	Gate-to-Body Leakage Current	V_{GS} = ±25 V, V_{DS} = 0 V	-	-	±10	μΑ
ON CHARAC	TERISTICS					
V _{GS(th)}	Gate Threshold Voltage	V_{GS} = V_{DS} , I_D = 250 μ A	3.0	-	5.0	V
R _{DS(on)}	Static Drain-to-Source On Resistance	V_{GS} = 10 V, I _D = 2 A	-	1.65	2.00	Ω
9FS	Forward Transconductance	$V_{DS} = 20 \text{ V}, \text{ I}_{D} = 2 \text{ A}$	-	5	-	S
DYNAMIC CH	HARACTERISTICS	-				
C _{iss}	Input Capacitance	V_{DS} = 25 V, V_{GS} = 0 V, f = 1 MHz	-	450	600	pF
C _{oss}	Output Capacitance		-	50	65	
C _{rss}	Reverse Transfer Capacitance	1	-	5	7.5	
Q _{g(tot)}	Total Gate Charge at 10 V	$V_{DS} = 400 \text{ V}, \text{ I}_{D} = 4 \text{ A},$	-	10	13	nC
Q _{gs}	Gate-to-Source Gate Charge	V _{GS} = 10 V (Note 4)	-	2.5	-	
Q _{gd}	Gate-to-Drain "Miller" Charge	1	-	4	-	
SWITCHING	CHARACTERISTICS	-				
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 250 \text{ V}, \text{ I}_{D} = 4 \text{ A},$	-	15	40	ns
t _r	Turn–On Rise Time	V_{GS} = 10 V, R_{G} = 25 Ω (Note 4)	-	20	50	
t _{d(off)}	Turn-Off Delay Time	1	_	35	80	1
t _f	Turn-Off Fall Time	1	-	20	50	
DRAIN-SOU	RCE DIODE CHARACTERISTICS					
IS	Maximum Continuous Drain to Source Dio	de Forward Current	-	-	4	Α
I _{SM}	Maximum Pulsed Drain to Source Diode Fo	prward Current	-	-	16	
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0 V, I _{SD} = 4 A	-	-	1.4	V

V _{SD}	Drain to Source Diode Forward Voltage	V_{GS} = 0 V, I_{SD} = 4 A	-	-	1.4	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 V, I_{SD} = 4 A,$	-	230	-	ns
Q _{rr}	Reverse Recovery Charge	dI _F /dt = 100 A/µs	-	0.9	-	μC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.
4. Essentially independent of Operating Temperature Typical Characteristics.

TYPICAL CHARACTERISTICS

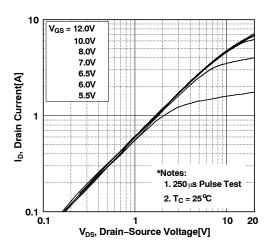


Figure 1. On–Region Characteristics

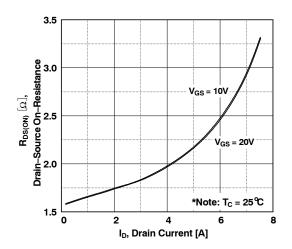


Figure 3. On–Resistance Variation vs. Drain Current and Gate Voltage

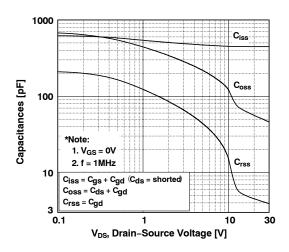
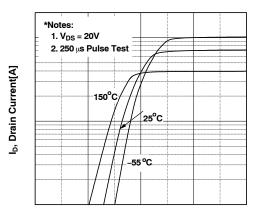


Figure 5. Capacitance Characteristics



V_{GS}, Gate-Source Voltage[V]

Figure 2. Transfer Characteristics

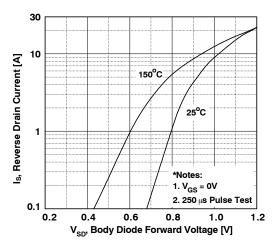


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

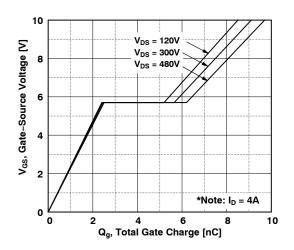
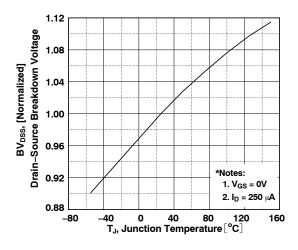
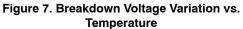


Figure 6. Gate Charge Characteristics

TYPICAL CHARACTERISTICS





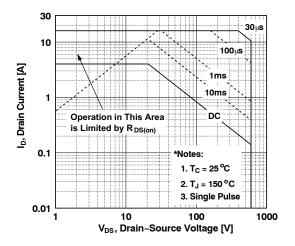


Figure 9. Maximum Safe Operating Area

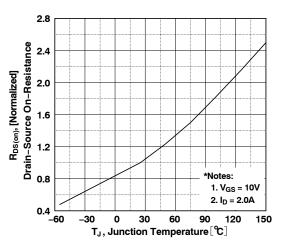


Figure 8. On–Resistance Variation vs. Temperature

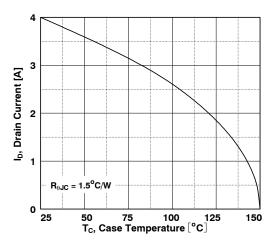


Figure 10. Maximum Drain Current vs. Case Temperature

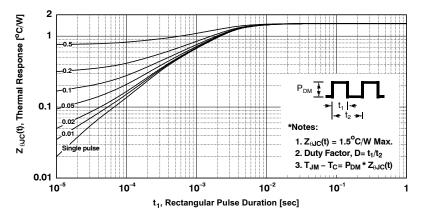
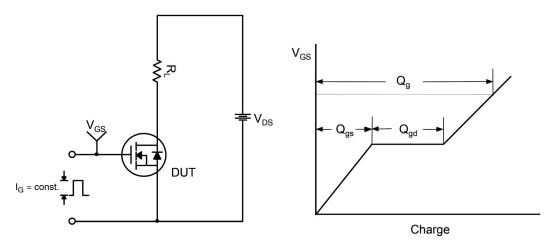


Figure 11. Transient Thermal Response Curve





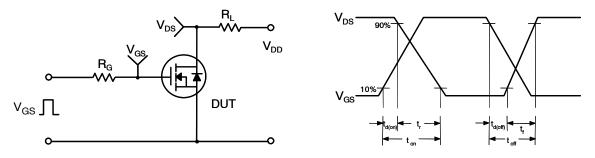


Figure 13. Resistive Switching Test Circuit & Waveforms

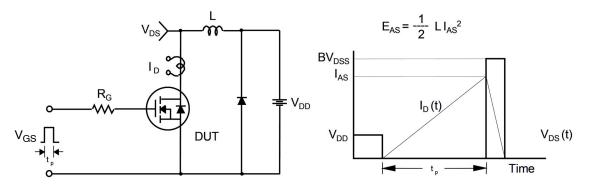
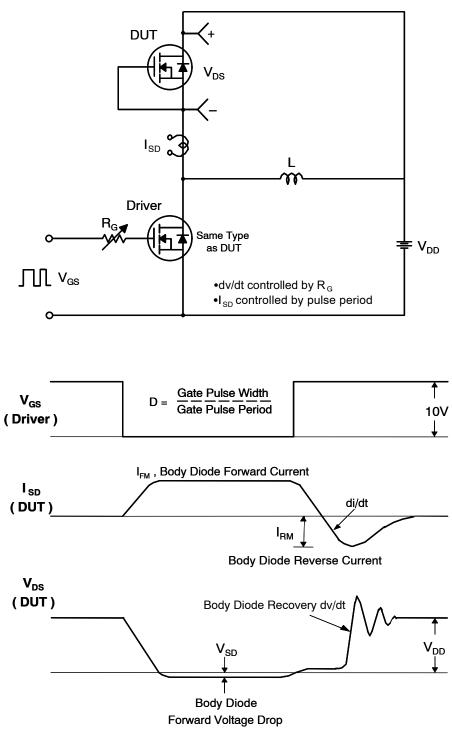
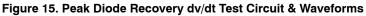


Figure 14. Unclamped Inductive Switching Test Circuit & Waveforms

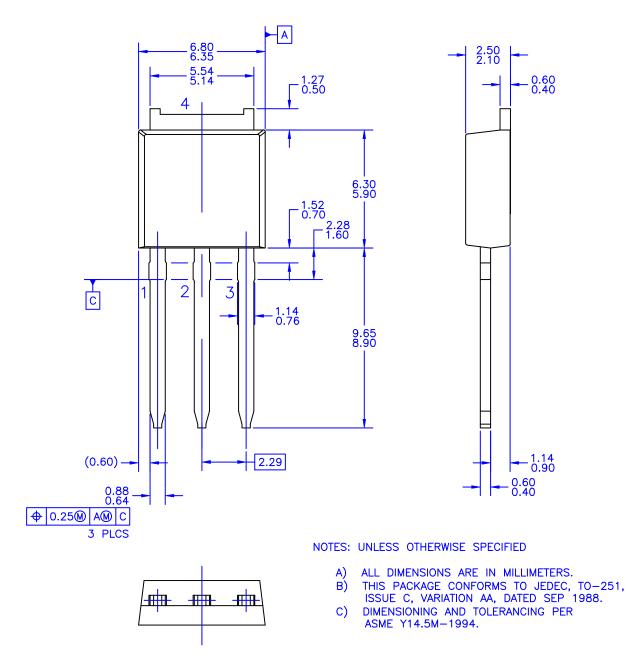






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DATE 30 SEP 2016



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